



DEFENSE LOGISTICS AGENCY
DEFENSE SUPPLY CENTER, COLUMBUS
POST OFFICE BOX 3990
COLUMBUS, OH 43216-5000

IN REPLY
REFER TO

DSCC-VQH-0236 (Ms. Tonnu/614-692-0586/bt)

August 3, 1999

SUBJECT: Reduction of Element Evaluation Testing, MIL-PRF-38534, FSC 5962

Mr. Dan Miller
M.S. Kennedy Corporation
8170 Thompson Road
Cicero, NY 13039-1187

Dear Mr. Miller:

Your proposal to reduce element evaluation testing for Class H integrated microcircuit, transistor, diode, passive element, and substrate, as allowed by paragraph 3.7.1 of MIL-PRF-38534 have been reviewed by this office.

As detailed in your April 6, 1999 letter, and further supported data in June 9, 1999, the reduced samples for wire bond evaluation, the sampling plans for internal visual, functional testing, and dimensional testing, and the elimination of electrical testing for microcircuit and semiconductor which have acceptable history are acceptable for use in compliant Class H products.

Even though paragraph 3.7.1 of MIL-PRF-38534 allows reductions in testing, your company is responsible for overall quality and reliability of the products. Such reductions in testing, while encouraged, do increase risk and will have a greater impact on completed products in the event of a failure.

If you have any questions, please contact Ms. Tonnu.

Sincerely,

A handwritten signature in black ink, appearing to read "Joseph Gemperline II".

JOSEPH GEMPERLINE
Chief
Hybrid Devices Team